

# Defect studies in BaTiO<sub>3</sub> ceramics using positron annihilation spectroscopy

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## Introduction

- BaTiO<sub>3</sub> (BT): high dielectric constant (up to 12000), positive temperature coefficient of resistivity in n-type BT [1]
- defects have strong influence on properties:
  - dominant native point defects should be vacancies [2,3]:
    - acceptor-type : V<sub>Ba</sub> and V<sub>Ti</sub>
    - donor-type : V<sub>O</sub>
  - grain boundaries (possible positron traps - increased density of crystal defects)

## Previous results

- early work: POLIS is sensitive to V<sub>Ba</sub> [4], supported by measurements on samples with varying stoichiometry [5]
- V<sub>Ba</sub> are predominant for La-doping level < 0.5 mol%, for La doping > 0.5 mol% V<sub>Ti</sub> is the most common anion vacancy defect [3]
- calculated positron lifetimes [6]:
  - τ(bulk) = 152 ps, τ(V<sub>Ba</sub>) = 293 ps, τ(V<sub>O</sub>) = 162 ps, τ(V<sub>Ti</sub>) = 204 ps.

## Objectives

- investigation of positron trapping as a function of temperature was not reported before → investigations as a function of temperature
- address defect types by suitable experiments (dependences on doping and annealing)
- investigate effect of grain size on positron trapping

## Experimental

### Sample preparation:

- production of BT powder by the mixed-oxide method [7]
  - BaCO<sub>3</sub> + TiO<sub>2</sub> (+La<sub>2</sub>O<sub>3</sub>) (+SnO<sub>2</sub>)
  - mixing and milling for 24 h
  - calcinating at 1100°C for 2 h
  - fine milling for 24 h
- commercial BT powder was used for high purity samples (for annealing experiments under variable O<sub>2</sub> pressure)
- BT powder was pressed into disks
- Sintering at: 1400°C (coarse grained samples), 1280°C (fine grained samples).

### Positron lifetime spectroscopy

- Fast-fast coincidence system, resolution 230 ps (FWHM)
- Positron source : <sup>22</sup>NaCl covered with Al-foil.

## Temperature dependent measurements

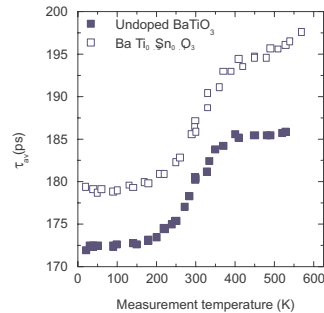


Fig. 1: τ<sub>av</sub> vs. T in undoped BaTiO<sub>3</sub> and BaTi<sub>0.9</sub>Sn<sub>0.1</sub>O<sub>3</sub>

- measured τ<sub>av</sub> is larger than calculated bulk lifetime (152 ps) [6]
  - **positron trapping at vacancy defects**

### Distinct temperature dependence of τ<sub>av</sub> - why ?

- Shallow traps: improbable, high dielectric constant screens the coulombic interaction
- Phase transition: phase transition at ~400 K in undoped BT can be ruled out because phase transition is shifted to ~300 K in BaTi<sub>0.9</sub>Sn<sub>0.1</sub>O<sub>3</sub> [8]
- Thermal expansion: can be ruled out, lattice constant increases only slightly with temperature [8]

### Probable explanation:

**Complex interplay between trapping at different defect types** but not yet well understood

## References

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## Annealing under variable oxygen pressure

- spectra decomposition failed in most cases
  - defect identification with POLIS not possible
  - annealing under variable oxygen pressure (pO<sub>2</sub>) to change defect concentration in a well defined way

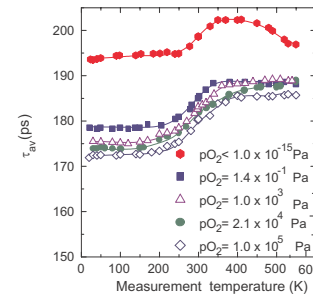


Fig. 2: τ<sub>av</sub> vs. T in undoped BT annealed under various oxygen pressures as indicated. Annealing was done at 1200°C for 2h.

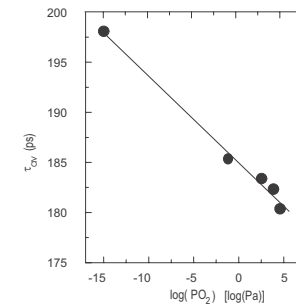


Fig. 3: τ<sub>av</sub> at 300 K in undoped BT as a function of log pO<sub>2</sub>

- increase of τ<sub>av</sub> with pO<sub>2</sub> indicates positron trapping at V<sub>O</sub>
- but measured τ<sub>av</sub> is higher than 162 ps (calculated for V<sub>O</sub>) [6]
- higher lifetime of 293 ps was calculated for V<sub>Ba</sub> [6]

→ **Neutral complex V<sub>Ba</sub><sup>II</sup>-V<sub>O</sub><sup>II</sup> is the most probable defect**

## Effect of grain size on positron trapping

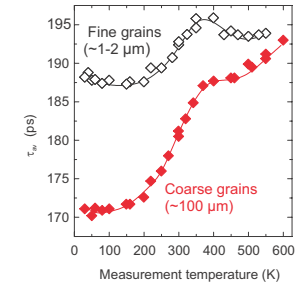


Fig. 4: τ<sub>av</sub> vs. T in undoped BT with different grain size.

- Grain size 1 μm: ~ 30 % of all positrons can reach the grain surface [9]
- Grain size 100 μm: fraction of positrons reaching the surface is negligible [9]
- **no influence of grain boundaries on positron trapping in coarse grained samples** (all other in the present work)

## Vacancies in donor (La) doped BaTiO<sub>3</sub>

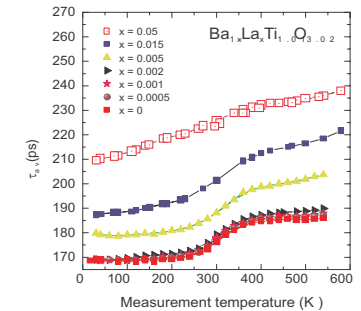


Fig. 5: τ<sub>av</sub> vs. T in La-doped BT. The La contents are indicated in the figure.

$$[\text{La}_{\text{Ba}}] + p = 2[\text{V}_{\text{Ba}}^{\text{II}}] + 4[\text{V}_{\text{Ti}}^{\text{III}}] + n$$

→ donor doping enhances formation of acceptor-type vacancies

→ positrons are trapped at V<sub>Ba</sub> or V<sub>Ti</sub>